

Technical Committees

Computer-Aided Design

W. H. KU
School of Elec. Eng.
Phillips Hall
Cornell Univ.
Ithaca, NY 14853

Submillimeter-Wave Techniques

K. J. BUTTON
Bldg. NW-14
Massachusetts Inst Technol.
Cambridge, MA 02133

Microwave and Millimeter-Wave Solid-State Devices

E. D. COHEN
Naval Electronic Systems Comd.
Elex. 03V
National Center #1
Washington, DC 20360

H. J. KUNO
Hughes Aircraft
3100 W. Lomita Blvd.
Torrance, CA 90509

Microwave Ferrites

C. R. BOYD, JR.
Microwave Applications Group
3030 Industrial Parkway
Santa Maria, CA 93455

Microwave Systems

F. IVANEK
Farinon Electric Operation
Harris Corp.
1691 Bayport Ave.
San Carlos, CA 94070

Microwave Network Theory

A. E. WILLIAMS
COMSAT LABS
22300 Comsat Dr.
Clarksburg, MD 20734

Microwave Acoustics

R. S. KAGIWADA
TRW Defense and Space Syst. Group
Elec. Syst. Div.
1 Space Park
Redondo Beach, CA 90278

Microwave High-Power

H. GOLDIE
Westinghouse Electric Corp.
Advanced Technology Labs.
P.O. Box 1521, MS-3716
Baltimore, MD 21203

Microwave Biological Effects and Medical Applications

O. P. GANDHI
Dep. Elec. Eng.
Univ. Utah
Salt Lake City, UT 84112

Microwave Low Noise Techniques

J. J. WHELEHAN, JR.
Eaton Corp. AIL Div.
Walt Whitman Rd.
Melville, NY 11747

Digital Microwave Systems

P. T. GREILING
Hughes Res. Labs.
3011 Malibu Canyon Rd.
Malibu, CA 90265

Fiber and Integrated Optics

W. S. C. CHANG
Dep. Elec. Eng. and Computer Sci.
C-014
Univ. California, San Diego
La Jolla, CA 92093

Microwave and Millimeter-Wave Integrated Circuits

B. E. SPIELMAN
U. S. Naval Res. Lab.
4555 Overlook Ave.
Washington, DC 20375

Microwave Measurements

H. G. OLTMAN, JR.
Hughes Aircraft Co.
Bldg. 268/A54
8433 Fallbrook Ave.
Canoga Park, CA 91304

Microwave Field Theory

T. ITOH
Dep. Elec. Eng.
The Univ. Texas, Austin, Box 7728
Austin, TX 78712

Automatic RF Techniques Group

M. A. MAURY, JR.
Maury Microwave Corp.
8610 Helms Ave.
Cucamonga, CA 91730

Technical Committees Chairman

B. E. SPIELMAN
U. S. Naval Res. Lab.
4555 Overlook Ave.
Washington, DC 20375

EDITORIAL BOARD

Editor

T. Itoh

S. Adam
A. T. Adams
J. Amoss
D. B. Anderson
J. A. Arnaud
J. R. Ashley
N. F. Audeh
A. J. Bahr
J. W. Bandler
H. E. M. Barlow
F. S. Barnes
R. H. T. Bates
E. F. Belohoubek
P. Bhartia
J. Bradshaw
D. I. Breitzer
M. Brodwin
C. Buntschuh
J. J. Burke
H. Bussey
K. J. Button
C. A. Cain
H. J. Carlin
P. H. Carr
K. S. Champlin
W. S. C. Chang
M. Chodorow
J. Citerne
S. B. Cohn
R. E. Collin
H. M. Cronson
E. Cristal
W. R. Curtice
J. B. Davies
L. E. Davis
M. E. Davis
J. E. Degenford
E. Denlinger
L. E. Dickens
C. H. Durney

R. Eisenhart
W. J. English
G. W. Farnell
L. B. Felsen
H. Fukui
Z. Galani
R. V. Garver
V. G. Gelinovatch
J. W. Gewartowski
C. S. Gledhill
A. Gopinath
H. Gruenberg
M. S. Gupta
A. W. Guy
U. Gysel
G. I. Haddad
M. A. K. Hamid
R. F. Harrington
W. Harth
H. L. Hartnagel
G. L. Heiter
J. Helszajn
M. E. Hines
D. T. Hodges
W. E. Hord
M. C. Horton
A. Q. Howard, Jr.
H. Howe, Jr.
W. J. Ince
M. Iskander
T. Itoh
P. B. Johns
W. R. Johns
A. K. Jordan
D. Kajfez
A. J. Kelly
A. R. Kerr
P. Khan
R. H. Knerr
Y. Konishi

A. Konrad
M. K. Krage
J. G. Kretzschmar
H. J. Kuno
K. Kurokawa
R. Levy
L. Lewin
M. Maeda
S. L. March
D. Marcuse
D. Masse
G. L. Matthaei
P. R. McIsaac
M. W. Medley, Jr.
S. E. Miller
J. W. Mink
N. Morita
W. W. Mumford
Y. Naito
H. Okean
T. Okoshi
A. A. Oliner
K. Oscar
C. Pask
D. Parker
J. Perini
B. S. Perlman
D. F. Peterson
R. A. Pucel
J. P. Quine
C. Rauscher
C. Ren
J. D. Rhodes
E. Rivier
G. P. Rodrigue
A. E. Ros
A. Rosen
F. J. Rosenbaum
S. W. Rosenthal
H. E. Rowe

T. E. Rozzi
C. T. Rucker
A. A. M. Saleh
E. W. Sard
W. O. Schlosser
M. V. Schneider
W. E. Schroeder
H. Schwan
P. Silvester
H. Sobol
P. I. Somlo
A. W. Snyder
K. Solbach
B. E. Spielman
W. Steenaart
W. H. Steier
Y. Takayama
C. H. Tang
J. J. Taub
F. J. Tischer
V. Tripathi
W. C. Tsai
R. S. Tucker
A. Uhler, Jr.
W. A. G. Voss
J. J. Wang
H. C. Wang
J. A. Weiss
W. T. Weeks
S. H. Wemple
R. J. Wenzel
H. A. Wheeler
L. A. Whicker
J. F. White
A. G. Williamson
I. Wolff
E. Yamashita
L. Young

INFORMATION FOR AUTHORS

IEEE TRANSACTIONS ON MICROWAVE THEORY AND TECHNIQUES is published monthly. Manuscripts should be prepared especially for publication in this TRANSACTIONS and submitted to the Editor at the address listed inside the front cover. The manuscripts must be typed double-spaced on 22×28 cm ($8\frac{1}{2} \times 11$ in) sheets. Three copies of both the manuscript and accompanying illustrations should be submitted. A list of illustrations should be included in each copy of the manuscript. Original illustrations should not be submitted initially. They will be called for if the paper is accepted for publication. Also, an author whose manuscript is accepted as a PAPER (but not as a SHORT PAPER) is requested to submit a short biography and a clear, glossy portrait upon acceptance. Each manuscript must include an abstract of not more than 200 words. The Editor reserves the right to return without a review manuscripts exceeding approximately 20 double-spaced typewritten pages plus 20 figures. LETTERS are generally limited to comments and replies to material previously published in this TRANSACTIONS, suggestions for new work, errata, and other exceptionally short articles. "Information for IEEE Authors" is available upon request from the IEEE Publications Department, 345 East 47th Street, New York, NY 10017.

Copyright

It is the policy of the IEEE to own the copyright to the technical contributions it publishes on behalf of the interest of the IEEE, its authors, and their employers, and to facilitate the appropriate reuse of this material by others. To comply with the U.S. Copyright Law, authors are required to sign an IEEE Copyright Form before publication. This form, a copy of which appears in each January issue of this TRANSACTIONS, returns to authors and their employers full rights to reuse their material for their own purposes. Authors must submit a signed copy of this form with their manuscripts.

Clearance of Manuscripts

The IEEE must of necessity assume that materials presented at its meetings or submitted to its publications are properly available for general dissemination to the audiences these activities are organized to serve. It is the responsibility of the author, not the IEEE, to determine whether disclosure of their material requires the prior consent of other parties, and if so, to obtain it.

Publication Policy

Papers will be reviewed for their technical merit, and decisions to publish will be made independently of an author's ability or willingness to pay page charges. *Voluntary page charges* of \$95 per printed page will be requested for papers of five pages or less. Page charges of \$100 per page are mandatory for each page in excess of five printed pages. Also, the MTT-S Administrative Committee has established a quota for the number of pages printed in each issue of this TRANSACTIONS whose costs are not defrayed by payment of page charges. Papers not covered by page charges may be delayed until space in an issue is available. The Editor can waive the quota requirement for exceptional papers or because of other extenuating circumstances.